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Measuring methods for semiconductor photocouplers

标准名称半导体光电耦合器测试方法

(English Translation)

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What this standard covers

This Standard specifies the semiconductor optocoupler (hereinafter referred to as "devices") test method. This Standard applies to semiconductor optocoupler.

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Standards quoted by this document

GB/T 2421.1-2008; GB/T 11499-2001; GB/T 15651-1995